# PCFG75T65MQF

# **IGBT Die**

Using novel field stop IGBT technology, ON Semiconductor's new series of field stop 4<sup>th</sup> generation IGBTs offer the optimum performance for solar inverter and UPS applications where low conduction and switching losses are essential.

#### **Features**

- Maximum Junction Temperature:  $T_J = 175^{\circ}C$
- Positive Temperature Co-efficient for Easy Parallel Operating
- High Current Capability
- Low Saturation Voltage:  $V_{CE(sat)} = 1.42 \text{ V (Typ.)}$  @  $I_C = 75 \text{ A}$
- High Input Impedance
- Fast Switching
- Tighten Parameter Distribution

## **Typical Applications**

- Solar Inverters
- UPS Systems

#### **MECHANICAL DATA**

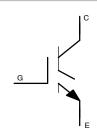
Parameter	Mils	μm	
Die Size	208.66 × 169.29	5300 x 4300	
Gate Pad Size	185.59 × 141.49	4714 x 3593.9	
Emitter Pad Size	31.38 × 56.17	797 x 1426.8	
Die Thickness	2.48	63	
Scribe Width	80 μm		
Top Metal	5 μm AlSiCu		
Back Metal	1.05 μm Al/NiV/Ag		
Topside Passivation	Silicon Nitride		
Wafer Diameter	200 mm		
Max Possible Die Per Wafer	1070		
Recommended Storage Environment	In original container, in dry nitrogen, < 3 months at ambient temperature of 23°C		



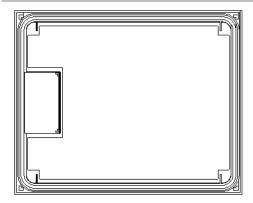
## ON Semiconductor®

www.onsemi.com

 $V_{RCE}$  = 650 V  $I_{C}$  = Limited by  $T_{j(max)}$ 



**IGBT Die** 



**DIE Outline** 

### **ORDERING INFORMATION**

Device	Inking?	Shipping Method
PCFG75T65MQF	No	Sawn Wafer on Tape

## PCFG75T65MQF

#### **MAXIMUM RATINGS**

Parameter	Symbol	Value	Unit	
Collector to Emitter Voltage, T <sub>J</sub> = 25°C	V <sub>CES</sub>	650	V	
Gate to Emitter Voltage	V <sub>GES</sub>	±20	V	
Collector Current @T <sub>C</sub> = 25°C	I <sub>C</sub>	(Note 1)	Α	
Pulsed Collector Current	I <sub>CM</sub>	300	Α	
Operating Junction Temperature	T <sub>J</sub>	-40 to +175	°C	
Storage Temperature Range	T <sub>STG</sub>	-17 to +25	°C	

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

- 1. Depending on the thermal properties of assembly.
- 2. Not subject to production test verified by design/characterization.

## **ELECTRICAL CHARACTERISTICS** (T<sub>J</sub> = 25°C unless otherwise specified)

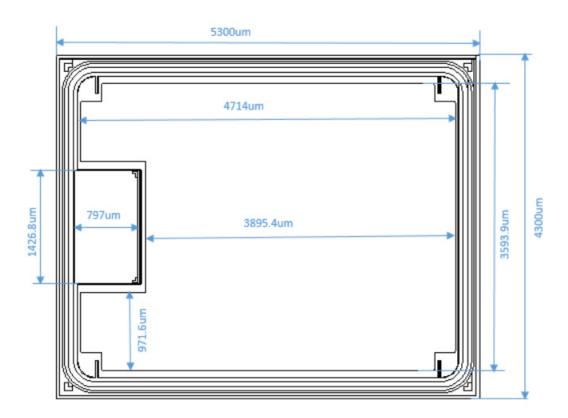
Parameter	Test Conditions	Symbol	Min	Тур	Max	Unit
OFF CHARACTERISTICS		•		•	•	
Collector-Emitter Breakdown Voltage	$V_{GE} = 0 \text{ V}, I_{C} = 1 \text{ mA}$	BV <sub>CES</sub>	650			V
Temperature Coefficient of Breakdown Voltage	I <sub>C</sub> = 1 mA, reference to 25°C	$\Delta BV_{CES}/\Delta T_{J}$		0.7		V/°C
Collector-Emitter Cutoff Current	V <sub>GE</sub> = 0 V, V <sub>CE</sub> = V <sub>CES</sub>	I <sub>DSS</sub>			250	μΑ
Gate Leakage Current	V <sub>CE</sub> = 0 V, V <sub>GE</sub> = V <sub>GES</sub>	I <sub>GSS</sub>			±400	nA
ON CHARACTERISTICS					-	
G-E Threshold Voltage	$V_{GE} = V_{CE}$ , $I_C = 60 \text{ mA}$	V <sub>GE(th)</sub>	2.6	4.6	6.4	V
Collector-Emitter Saturation Voltage	I <sub>C</sub> = 60 A, V <sub>GE</sub> = 15 V	V <sub>CE(sat)</sub>		1.42	1.9	V
	I <sub>C</sub> = 60 A, V <sub>GE</sub> = 15 V, T <sub>C</sub> = 175°C	1		1.7		V
DYNAMIC CHARACTERISTICS					-	
Input Capacitance	$V_{GE} = 0 \text{ V}, V_{CE} = 30 \text{ V}, f = 1 \text{ MHz}$	C <sub>ies</sub>		4677		pF
Output Capacitance		Coes		63		
Reverse Transfer Capacitance		C <sub>res</sub>		15		
GATE CHARGE CHARACTERISTICS		-				
Total Gate Charge	$V_{CE} = 400 \text{ V}, I_{C} = 60 \text{ A}, V_{GE} = 15 \text{ V}$	Qg		144		nC
Gate to Emitter Charge		Q <sub>ge</sub>		26		
Gate to Collector Charge		Q <sub>gc</sub>		35		

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

<sup>\*</sup>Switching characteristics and thermal properties depend strongly on module design and mounting technology.

For ordering, technique and other information on ON Semiconductor automotive bare die products, please contact automotivebaredie@onsemi.com.

### PCFG75T65MQF



(all dimensions in  $\mu$ m)

Figure 1. Die Layout

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